

**CIL**  
**EMU CRITICAL ITEMS LIST**

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Date: 12/22/91

12/24/91 SUPERSEDES 10/31/90

ANALYST:

NAME	F/M	OFF	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
CAUTION AND WARNING SYSTEM, ITEM 150 SV785970-13 (1)			2/IRB	150FM13: Fails at zero voltage, 5.6 volt power supply.	END ITEM: Loss of electrical power to operate CMS microprocessors.	<p>A. Design -</p> <p>Established reliability capacitors and resistors are qualified to applicable military standards and thermal shocked per Condition B Test Method 107 of MIL-STD-202. Microcircuits are qualified to the requirements of MIL-W-38510 and receive the burn-in of Class B parts of Method 5004 of MIL-STD-883.</p> <p>Transistors, diodes are qualified to the requirements of MIL-S-19500 and receive the burn-in of JANTRV level parts per the applicable methods, 1038, 1039, 1040 of MIL-STD-750. The electronic components are operating within the power derating requirements of SVHS2804 (derated to at least 75%). The printed circuit (PC) boards are fiberglass/epoxy per MIL-P-13949 type GP and manufactured in accordance with MIL-P-0006. Parts mounting and soldering is per MSPEC-STD-138 and MILS3500.4 (3A-1).</p> <p>The CMS is a mother/daughter board assembly. The daughter boards are held in place by a metal card guide which also provides thermal transfer from the boards to the CMS case. The top cover of the CMS exerts a downward force on the daughter boards to keep them properly seated to the mother board connectors.</p> <p>Flex Tape (Kapton Insulated, flexible flat conductor) instead of conventional Teflon coated wires is used to provide connections between the mother board and the external connectors. This prevents pinching of the conductor during item assembly. The PC board assemblies are conformal coated per MIL-A-4616 (Dow Corning RTV 3148) for environmental and humidity protection. Electrical connectors are environmentally sealed to prevent damage due to contamination and humidity.</p> <p>B. Test -</p> <p>Component Acceptance Test -</p> <p>Full functioning of the CMS is verified during Item AIP. Tests include continuity, logic latching, n-state sequencing, fault simulation, verification of status and fault messages, warning and alert tones activation, and BITE activation. These tests are conducted upon completion of random vibration testing (4.1g rms).</p> <p>PQA Test -</p> <p>The above electrical tests are repeated during PLSS PQA to verify CMS operation. The CMS is also operational during</p>

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NAME	FAILURE	FAILURE EFFECT	RAISONNALE FOR ACCEPTANCE
P/N	MODE &		
OFF	CAUSES		
2/108	OR11	150FM03:	

other #LSS PDR electrical tests such as sensor accuracy checks, Item 123 Fan Operation, Item 174 R108 checkout, and Solenoid Valve Actuation.

**Certification Test -**

The item completed the 15 year structural vibration and shock certification requirement during 10/83. EC's 42806-244 (odd jumper wires, odd diode CR221, change resistor R307), 42806-365-3 (eliminate Interference with #LSS, 42806-718 (overstressed resistor R583 due to an improper interface circuit delta data logger, software change, diode WR201 rewiring), 42806-962 and 42806-962-1 (transistor Q201 lead stress relief) have been incorporated and certified by stability or analysis since this configuration was tested.

**C. Inspection -**

Each circuit board, the flex tape, and connectors are inspected for damage and contamination prior to being placed into finished stowage. The CWS assembly is inspected internally and externally during AIP. All soldering is inspected by RS QA and OCMG QA per MIL-STD-200-4 (3A-1).

**D. Failure History -**

H-EMU-150-008B (6/26/89)

During a logic flow test, the CWS failed to start in the required time limit of ten seconds due to insufficient voltage at the CWS reset circuit. A larger voltage drop across the OR11 diode in series with the CWS reset logic circuitry did not provide the necessary voltage level, 5 volts, to trip the reset circuit within the required 10 seconds. EC 189502-327 tightens the diode screening requirement from a "forward voltage drop of .60 - .80 volts" to a "forward voltage drop of .60 -.72 volts at a forward current of 100 milliamperes" to increase the voltage supplied to the CWS reset logic circuitry.

**E. Ground Turnaround -**

Tested per FETH-II-001, Vacuum Chamber Performance, ORW Display Verification.

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ANALYST:

NAME	FAILURE	CAUSE	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
P/H	MODE B	CAUSES		
QTY	CRIT			
2/100	150FM13:			

F. Operational Use -

CREW Response -

PreEVA: Troubleshoot problem, if no success, consider EMU 3 if available. EMU no go for EVA.

EVA: When loss of OWS tones and displays detected, terminate EVA.

Training - Standard EMU training covers this failure mode.

Operational Considerations - Flight rules define and operational OWS are not able to monitor a valid status flag. EVA checklist procedures verify hardware integrity and system operational status prior to EVA. Real Time Data System allows ground monitoring of EMU systems.